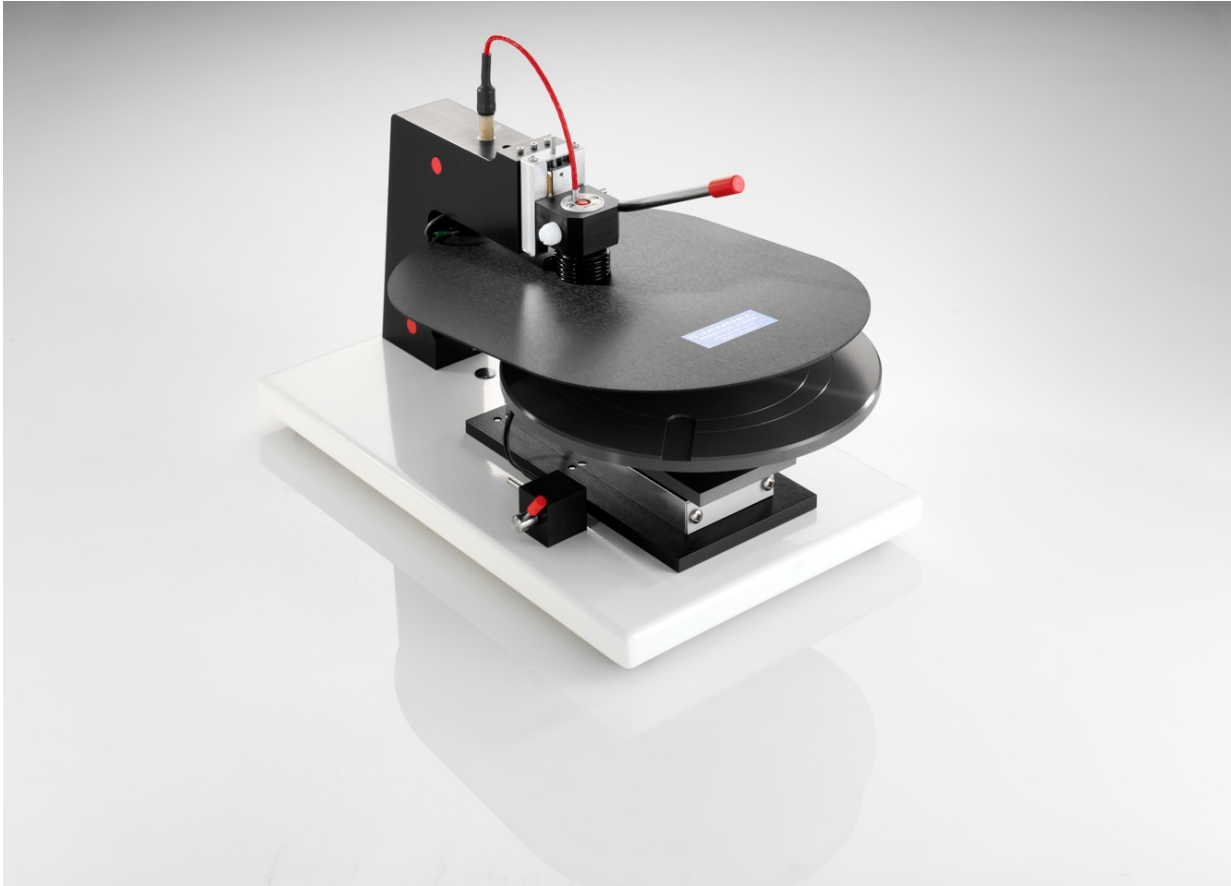


Multiposition Probe Stand

 **JANDEL**

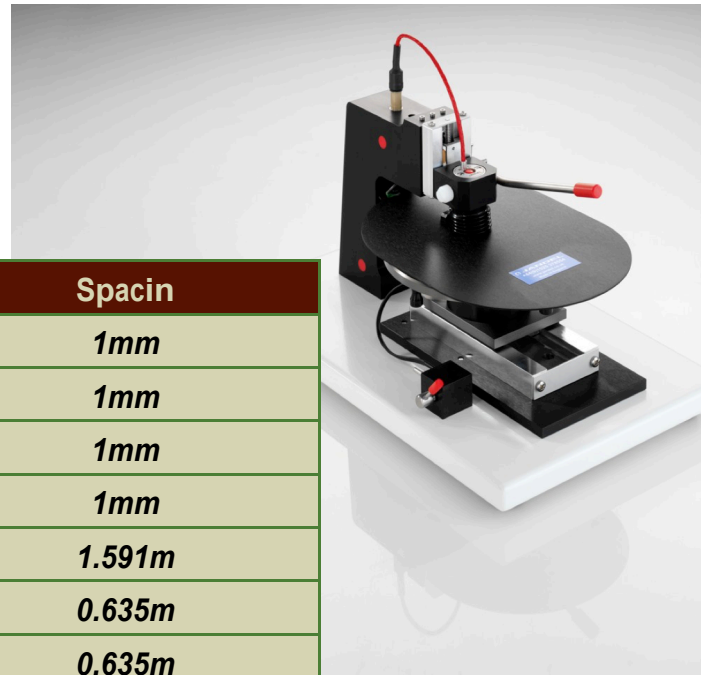


Jandel Engineering Limited offers the Multiposition Probe stand as a solution for measurements on wafers up to 200mm diameter). The probe is available in two sizes at the same cost. One size is for wafers up to 150mm diameter and the second for wafers up to 200mm diameter. If small sized wafers are to be measured the smaller version is more suitable for placement of the wafers on the measurement table. The θ movement clicks in four positions at 90 degrees and the linear movement in up to 10 positions giving repeat placement accuracy of +/- 1mm.

Multiposition Probe Stand

Max. sample size	150mm wafer (200mm wafer on request at no extra cost)
Max. sample thickness	Samples up to 4mm thick can be measured
Microswitch	Prevents current flow when probe is not in contact with the sample
Manual Control	Simple lever operation for probe contact and removal
Simple set up	Single wire connects the probe stand and measurement equipment
X-θ Stage	Repositioning accuracy of +/-1mm

Available Probes



Type	Tip	Forc	Spacin
A	40u	100g	1mm
B	100u	100g	1mm
C	200u	100g	1mm
D	500u	70g	1mm
E	40u	200g	1.591m
F	40u	100g	0.635m
G	100u	100g	0.635m
H	200u	100g	0.635m

Type A-D and F-H are user adjustable in the range 60g-150g and supplied at

If you require any further information on the Multiposition Probe please contact us using the details below